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Type: **Talk**

## **TCAD and recent defect studies**

*Friday 18 October 2019 08:30 (22 minutes)*

This talk will expone recent simulation techniques for analyzing acceptor removal, new defects model (in particular the pentatrap Hamburg model and the new Perugia model) and how to take into account effects related to temperature and the signal processing from the electronics front end. Acceptor removal in LGAD, for example, is now a problem under study and its simulation needs to define ad hoc device models, to consider the appropriate trap emulation and also to take into account, for timing purposes, the front end signal processing part.

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